



SHENZHEN MENGKE ELECTRONICS TECHNOLOGY CO.,LTD

SOT-23-6L Plastic-Encapsulate MOSFETs

MK6601

Complementary Enhancement Mode Field Effect Transistor

N-Channel

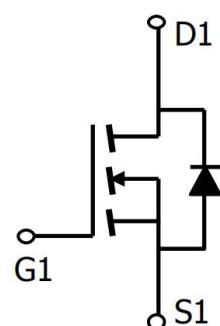
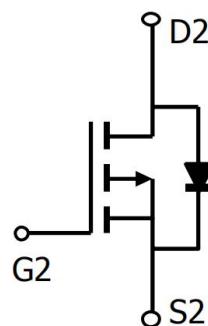
V(BR)DSS	RDS(on)MAX	ID
30 V	60mΩ@ 10V	4A
	75mΩ@ 4.5V	
	115mΩ@ 2.5V	

P-Channel

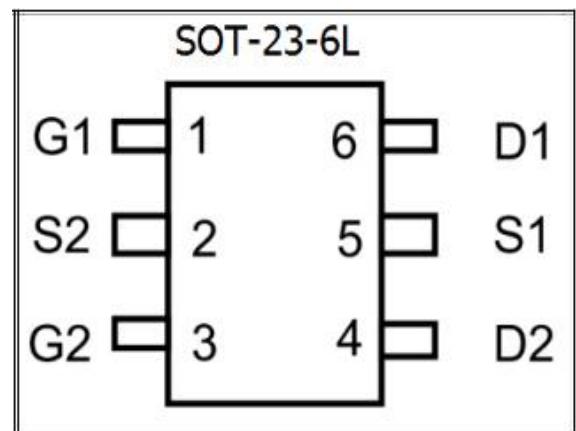
V(BR)DSS	RDS(on)MAX	ID
-30	120mΩ@ -10V	-4A
	170mΩ@ -4.5V	
	250mΩ@ -2.5V	

FEATURE:

※ TrenchFET Power MOSFET

MARKING:**F1PA-MK****Equivalent Circuit:****n-channel****p-channel****General Description:**

The MK6601 uses advanced trench technology to provide excellent RDS(ON) and low gate charge. The complementary MOSFETs form a high-speed power inverter, suitable for a multitude of applications. Standard Product MK6601 is Pb-free (meets ROHS & Sony 259 specifications).

**Maximum ratings (Ta=25°C unless otherwise noted)**

Parameter	Symbol	Max n-channel	Max P-channel	Unit
Drain-Source Voltage	VDS	30	-30	V
Gate-Source Voltage	VGS	±12	±12	
Continuous Drain Current	ID	4	-4	A
Pulsed Diode Current	IDM	30	-30	
Continuous Source-Drain Current(Diode Conduction)	IS	1.5	-1.3	
Power Dissipation	PD	1.15	1.15	W
Thermal Resistance from Junction to Ambient (t≤10s)	R _{θJA}	125	125	°C/W
Operating Junction	T _J	150	150	°C
Storage Temperature	T _{STG}	-55~+150	-55~+150	°C

**N-channel****N-channel MOSFET Electrical Characteristics (Ta = 25 °C Unless Otherwise Noted)**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-source breakdown voltage	V(BR)DSS	VGS = 0V, ID = 250µA	30			V
Gate-source threshold voltage	VGS(th)	VDS = VGS, ID = 250µA	0.6		1.4	V
Gate-body leakage current	IGSS	VDS = 0V, VGS = ±12V			±100	nA
Zero gate voltage drain current	IDSS	VDS = 30V, VGS = 0V			1	µA
Static Drain-Source On-Resistance	RDS(on)	VGS = 10V, ID = 3.4A		50	60	mΩ
		VGS = 4.5V, ID = 3A		60	75	mΩ
		VGS = 2.5V, ID = 2.8A		88	115	mΩ
Forward transconductancea	gfs	VDS = 5V, ID = 4A		8		S
Diode forward voltage	VSD	IS= 1A, VGS=0V		0.8	1.3	V
Maximum Body-Diode Continuous Current	IS				1.5	A
Dynamic						
Input capacitance	Ciss	VDS = 15V, VGS = 0V, f=1MHz		390		pF
Output capacitance	Coss			54.5		pF
Reverse transfer capacitanceb	Crss			41		pF
Total gate charge	Qg	VDS = 15V, VGS = 10V, ID = 4A		4.5		nC
Gate-source charge	Qgs			1.4		nC
Gate-drain charge	Qgd			0.6		nC
Gate resistance	Rg	f=1MHz		3		Ω
Switchingb						
Turn-on delay time	td(on)	VDS= 15V RL=5Ω, ID = 4A, VGS= 10V, Rg=6Ω		4		ns
Rise time	tr			2		ns
Turn-off delay time	td(off)			22		ns
Fall time	tf			3		ns
Body Diode Reverse Recovery Time	Trr	IF=4A, dI/dt=100A/µs		11		ns
Body Diode Reverse Recovery Charge	Qrr	IF=4A, dI/dt=100A/µs		5.5		nC

Note :

1. Repetitive Rating : Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, t < 10 sec.
3. Pulse Test : Pulse Width≤300µs, Duty Cycle ≤ 2%.
4. Guaranteed by design, not subject to production testing.



P-channel

P-channel MOSFET Electrical Characteristics ($T_a = 25^\circ\text{C}$ Unless Otherwise Noted)

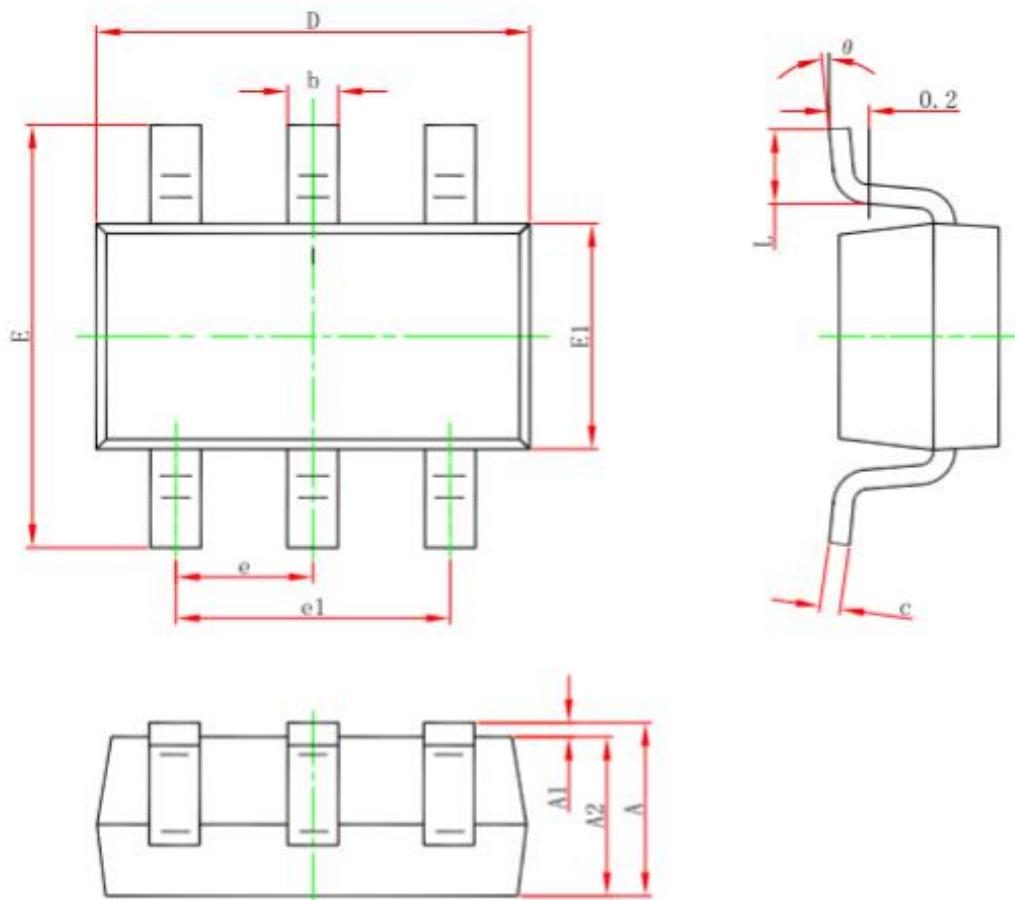
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-source breakdown voltage	V(BR)DSS	VGS = 0V, ID = -250μA	-30			V
Gate-source threshold voltage	VGS(th)	VDS = VGS, ID = -250μA	-0.6		-1.4	V
Gate-body leakage current	IGSS	VDS = 0V, VGS = ±12V			±100	nA
Zero gate voltage drain current	IDSS	VDS = -24V, VGS = 0V			-1	μA
Static Drain-Source On-Resistance	RDS(on)	VGS = -10V, ID = -2.5A		107	120	mΩ
		VGS = -4.5V, ID = -2A		135	170	mΩ
		VGS = -2.5V, ID = 1A		195	250	mΩ
Forward transconductancea	gfs	VDS = -5V, ID = -4A		8		S
Diode forward voltage	VSD	IS = -1A, VGS=0V		-0.8	-1.2	V
Maximum Body-Diode Continuous Current	IS				-1.4	A
Dynamic						
Input capacitance	Ciss	VDS = -15V, VGS = 0V, f=1MHz		409		pF
Output capacitance	Coss			55		pF
Reverse transfer capacitanceb	Crss			42		pF
Total gate charge	Qg	VDS = -15V, VGS = -10V, ID = -4A		4.8		nC
Gate-source charge	Qgs			1.4		nC
Gate-drain charge	Qgd			0.72		nC
Gate resistance	Rg	f=1MHz		12		Ω
Switchingb						
Turn-on delay time	td(on)	VDS= -15V RL = 4.4Ω, ID = -4A, VGS= -10V,Rg=3Ω		13		ns
Rise time	tr			10		ns
Turn-off delay time	td(off)			28		ns
Fall time	tf			13		ns
Body Diode Reverse Recovery Time	Trr	IF= -4A, dI/dt=100A/μs		26		ns
Body Diode Reverse Recovery Charge	Qrr	IF= -4A, dI/dt=100A/μs		15.6		nC

Note :

1. Repetitive Rating : Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t < 10$ sec.
3. Pulse Test : Pulse Width≤300μs, Duty Cycle ≤ 2%.
4. Guaranteed by design, not subject to production testing.



SOT-23-6L PACKAGE OUTLINE DIMENSIONS:



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
c	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
e	0.950(BSC)		0.037(BSC)	
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°



N-channel Typical Electrical AND Thermal Characteristics:

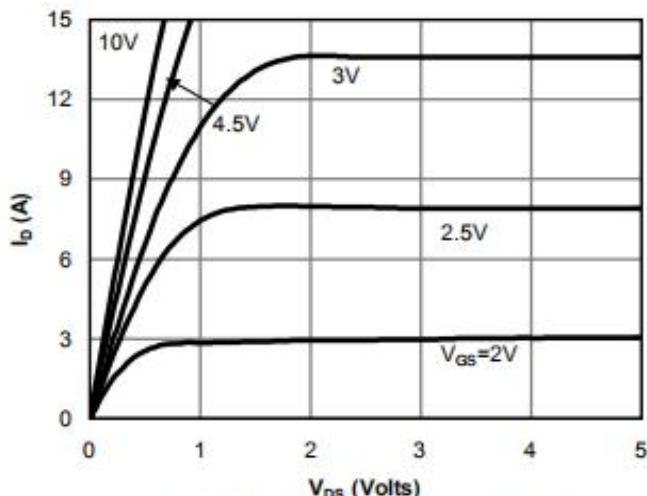


Fig 1: On-Region Characteristics

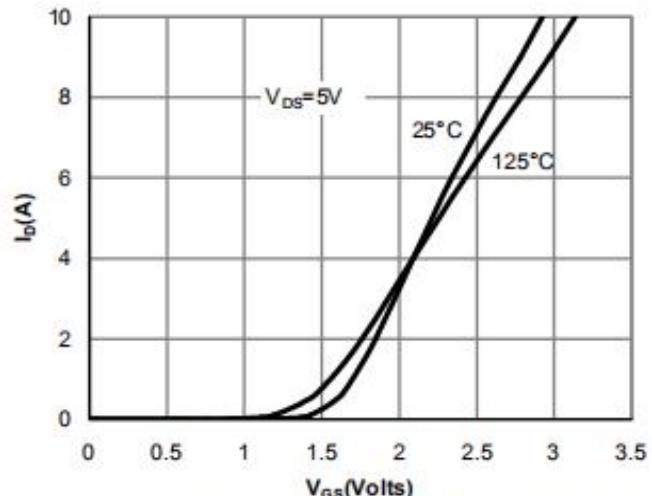


Figure 2: Transfer Characteristics

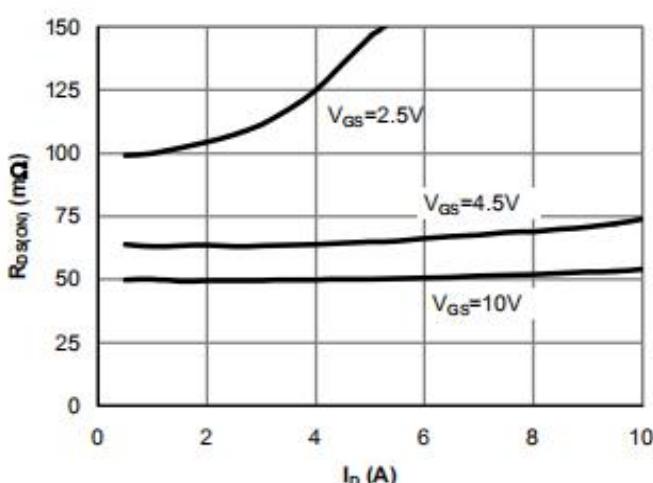


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

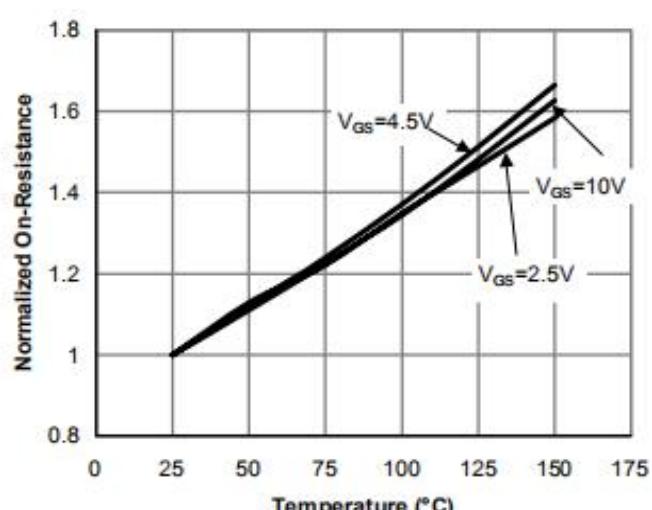


Figure 4: On-Resistance vs. Junction Temperature

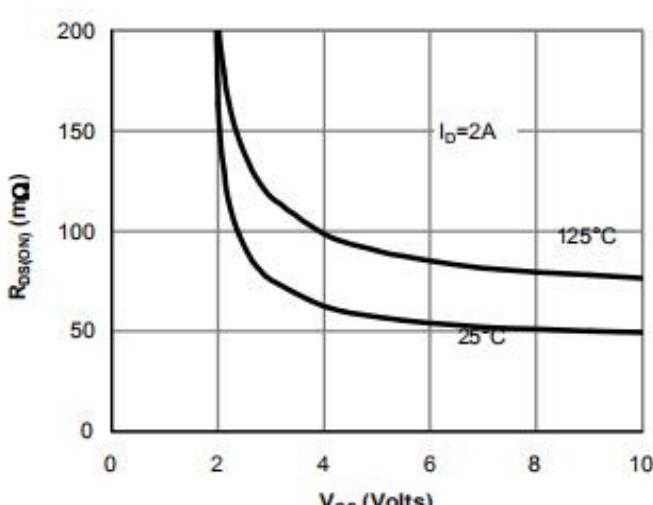


Figure 5: On-Resistance vs. Gate-Source Voltage

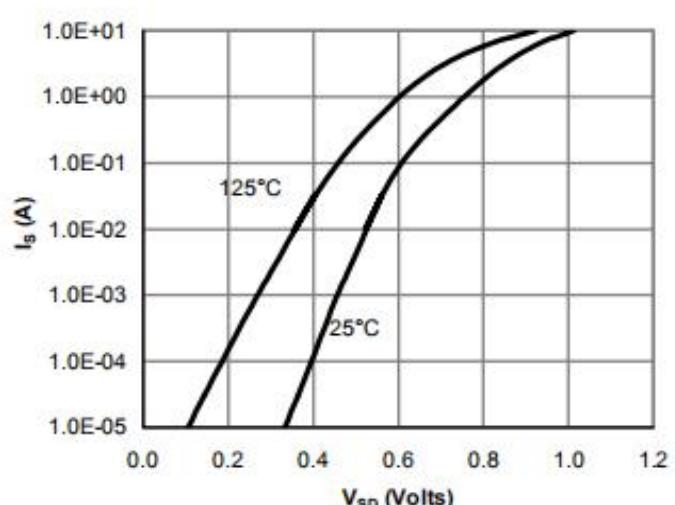
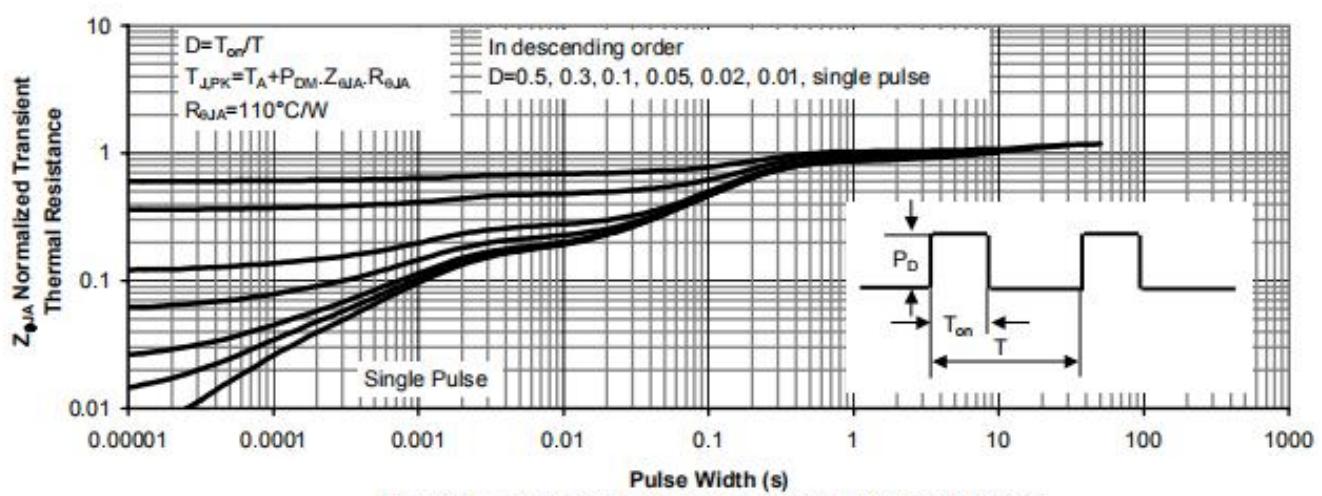
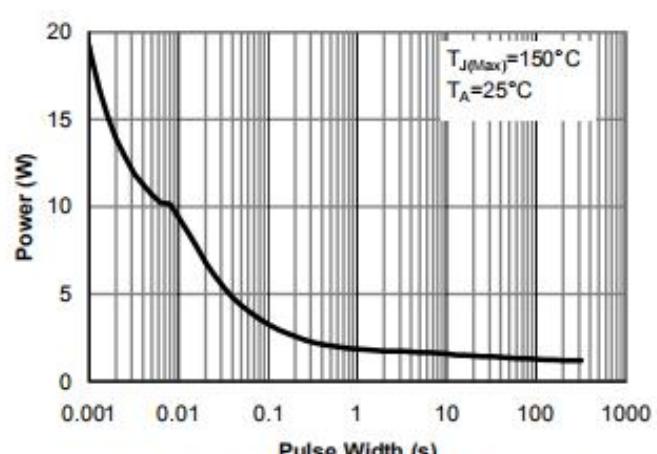
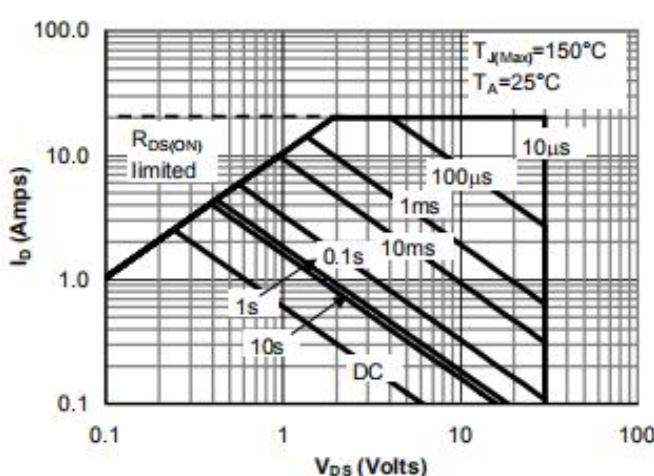
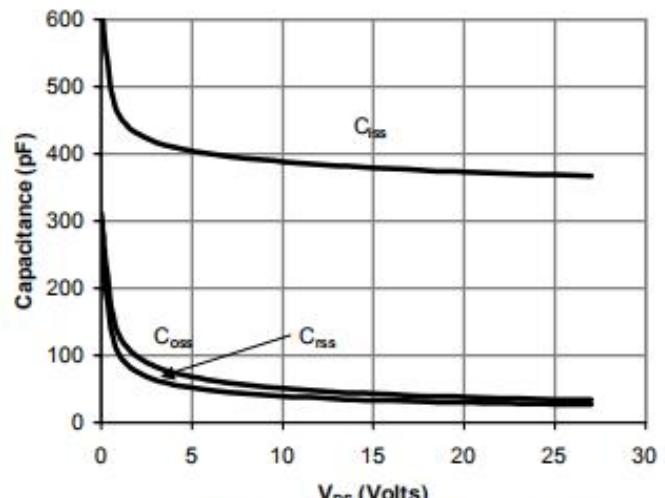
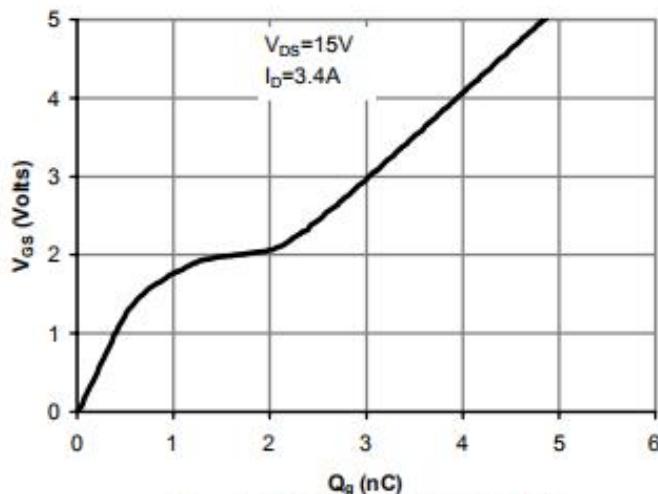


Figure 6: Body-Diode Characteristics



N-channel Typical Electrical AND Thermal Characteristics:





P-channel Typical Electrical AND Thermal Characteristics:

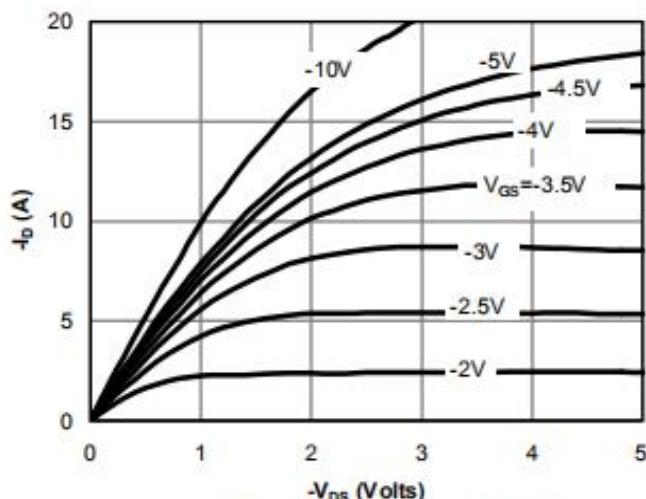


Fig 1: On-Region Characteristics

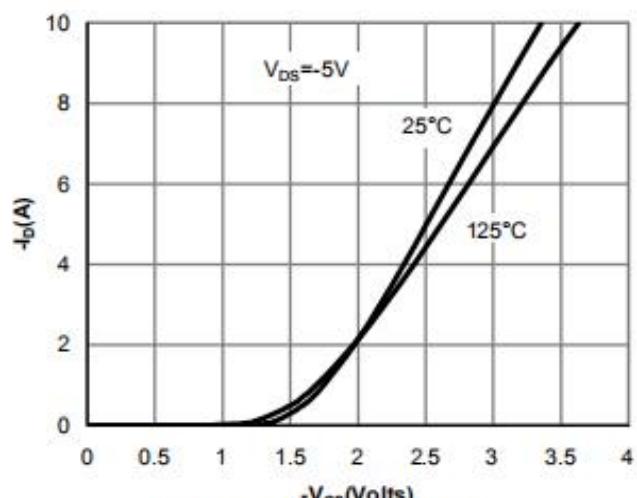


Figure 2: Transfer Characteristics

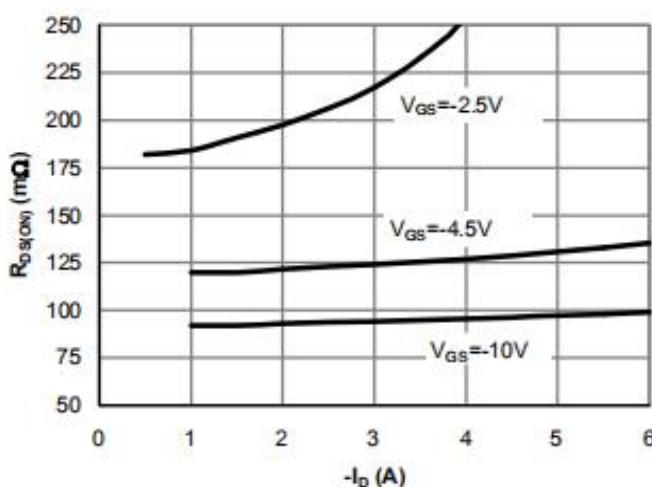


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

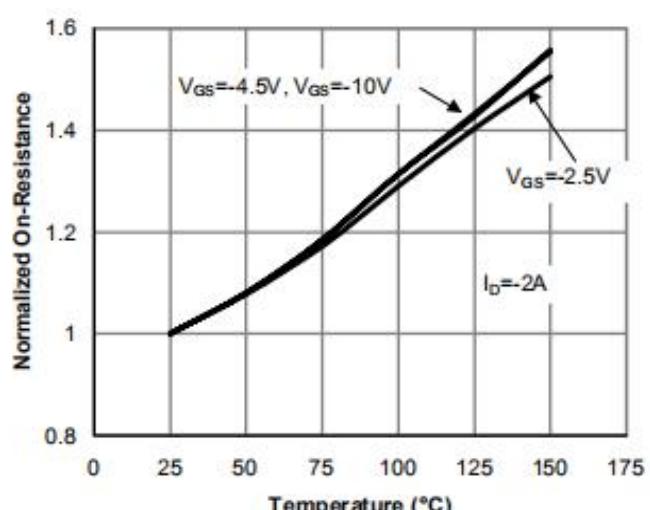


Figure 4: On-Resistance vs. Junction Temperature

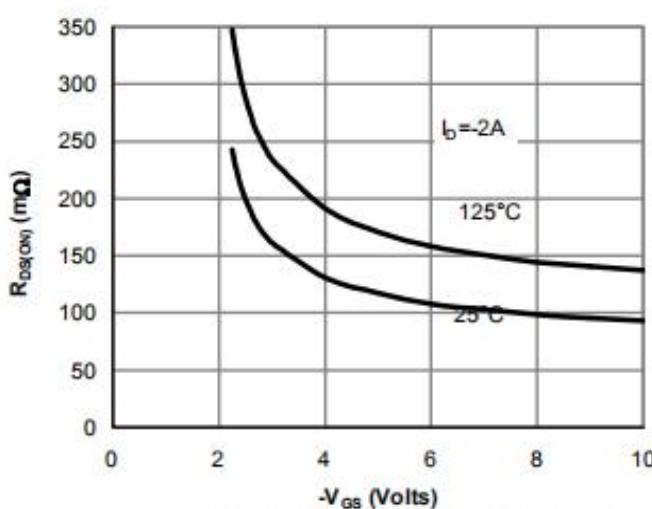


Figure 5: On-Resistance vs. Gate-Source Voltage

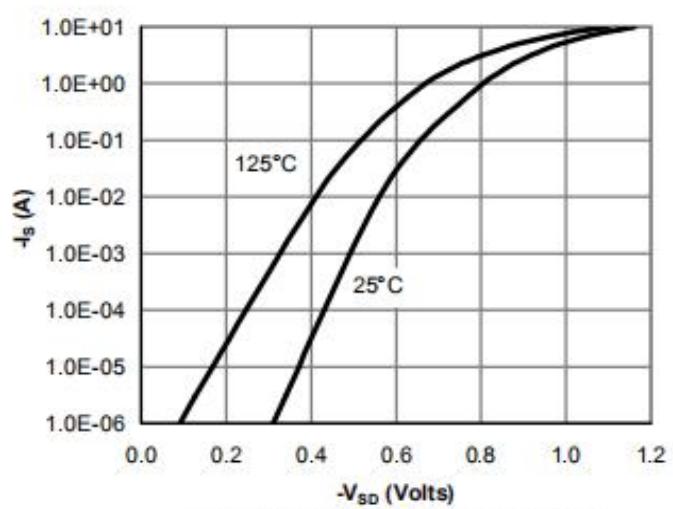


Figure 6: Body-Diode Characteristics



P-channel Typical Electrical AND Thermal Characteristics:

